


<b>Search Notes</b> 	<b>Application/Control No.</b> 10600014	<b>Applicant(s)/Patent Under Reexamination</b> CHATTERJEE ET AL.
	<b>Examiner</b> Lin, Shew-Fen	<b>Art Unit</b> 2166

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
East	12/1/2007	SFL
Consult Khanh Pham (Primary Examiner 2166)	12/3/2007	SFL

INTERFERENCE SEARCH			
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